


<b>Search Notes</b> 	<b>Application/Control No.</b> 10697108	<b>Applicant(s)/Patent Under Reexamination</b> BEISEL ET AL.
	<b>Examiner</b> Lee, Siu M	<b>Art Unit</b> 2611

SEARCHED			
Class	Subclass	Date	Examiner
375	224, 316	2/17/2007	Siu M. Lee
398	1-8	2/17/2007	Siu M. Lee
370	217-229	2/17/2007	Siu M. Lee

SEARCH NOTES			
Search Notes		Date	Examiner
EAST		2/17/2007	Siu M. Lee
Discuss the application with Cheih Fan		2/17/2007	Siu M. Lee
Discuss the amendment with Chieh Fan		8/21/2007	Siu M. Lee
EAST		8/22/2007	Siu M. Lee
EAST		3/26/2008	Siu M. Lee
Discuss the application with Chieh Fan		3/26/2008	Siu M. Lee
EAST		10/22/2008	Siu M. Lee
Discuss the amendment with Chieh Fan		10/22/2008	Siu M. Lee

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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